

Assurance Continuity Maintenance Report

BSI-DSZ-CC-0404-2007-MA-04

NXP Secure Smart Card Controller P5CD040V0B, P5CC040V0B, P5CD020V0B, P5CC021V0B and P5CD012V0B with specific IC Dedicated Software

from

NXP Semiconductors Germany GmbH



Common Criteria Recognition Arrangement for components up to EAL4

The IT product identified in this report was assessed according to the *Assurance Continuity: CCRA Requirements*, version 1.0, February 2004 and the developers Impact Analysis Report (IAR). The baseline for this assessment was the Certification Report, the Security Target and the Evaluation Technical Report of the product certified by the Federal Office for Information Security (BSI) under BSI-DSZ-CC-0404-2007.

The change to the certified product is at the level of test configurations before TOE delivery, a change that has no effect on assurance. A new version of the Configuration List is considered. No changes of hardware or IC dedicated software are applied, the TOE description of BSI-DSZ-CC-0404-2007 remains unchanged.

Consideration of the nature of the change leads to the conclusion that it is classified as a minor change and that certificate maintenance is the correct path to continuity of assurance.

Therefore, the assurance as outlined in the Certification Report BSI-DSZ-CC-0404-2007 is maintained for this version of the product. Details can be found on the following pages.

This report is an addendum to the Certification Report BSI-DSZ-CC-0404-2007.

Bonn, 23 July 2008



Assessment

The IT product identified in this report was assessed according to the *Assurance Continuity: CCRA Requirements* [1] and the Impact Analysis Report (IAR) [2]. The baseline for this assessment was the Certification Report of the certified product (Target of Evaluation, TOE) [3], the Security Target [4] and the Evaluation Technical Report for Composition [9].

The vendor for the NXP Secure Smart Card Controller P5CD040V0B, P5CC040V0B, P5CD020V0B, P5CC021V0B and P5CD012V0B with specific IC Dedicated Software, NXP Semiconductors Germany GmbH, submitted an IAR [2] to the BSI for approval. The IAR is intended to satisfy the requirements outlined in the document *Assurance Continuity: CCRA Requirements* [1]. In accordance with those requirements, the IAR describes (i) the changes made to the certified TOE, (ii) the evidence updated as a result of the changes and (iii) the security impact of the changes.

The NXP Secure Smart Card Controller P5CD040V0B, P5CC040V0B, P5CD020V0B, P5CC021V0B and P5CD012V0B with specific IC Dedicated Software was changed due to the latest modifications of the wave shape definitions of the ISO14443 standard and modified test methods defined in the ISO 10673-6 standard. The change is not significant from the standpoint of security, however the Configuration List requires a change in the version number from 1.2 to 1.6 and the Electrical Test Specification [10] from 2.0 to 6.0.

Two changes are added to previous Maintenance Processes BSI-DSZ-CC-0404-2007-MA-01 [6], BSI-DSZ-CC-0404-2007-MA-02 [7] and BSI-DSZ-CC-0404-2007-MA-03 [8]: Test configuration parameters regarding the wave shape definition and test pad configuration had been changed. The configuration mechanism is not changed, only the values programmed into EEPROM fuses are modified.

For the identification of a specific NXP P5CD0xxV0B chip family, the Device Coding Bytes stored in the EEPROM can be used: The value 25 hex for P5CD040V0B, 23 hex for P5CC040V0B, 21 hex for P5CD020V0B, 22 hex for P5CC021V0B and 20 hex for P5CD012V0B in Device Coding Byte DC2 identifies the chip configuration. As the TOE functionality did not change, it is indicated by the chip identifier T036B [3]. The Configuration List [5] was updated.

Conclusion

The change to the TOE is at the level of test configurations before TOE delivery, a change that has no effect on assurance. Examination of the evidence indicates that the changes performed are limited to an update of the Configuration List [5] and Electrical Test Specification [10]. The Security Target [4] is still valid for the changed TOE. Consideration of the nature of the change leads to the conclusion that it is classified as a minor change and that certificate maintenance is the correct path to continuity of assurance.

Therefore, BSI agrees that the assurance as outlined in the Certification Report [3] is maintained for this version of the product. This report is an addendum to the Certification Report [3].

References

- [1] Common Criteria document CCIMB-2004-02-009 "Assurance Continuity: CCRA Requirements", version 1.0, February 2004
- [2] Impact Analysis Report BSI-DSZ-CC-404-2007-MA-04, P5CD040/P5CC040/P5CD020/P5CC021/P5CD012 V0B, Revision 1.0, NXP Semiconductors Germany GmbH, 11. July 2008 (confidential document)
- [3] Certification Report BSI-DSZ-CC-0404-2007 for NXP Secure Smart Card Controller P5CD040V0B, P5CC040V0B, P5CD020V0B and P5CC021V0B each with specific IC Dedicated Software, Bundesamt für Sicherheit in der Informationstechnik, 5. July 2007
- [4] Security Target BSI-DSZ-CC-0404-2007, Evaluation of the NXP P5CD040/P5CC040/P5CD020/P5CC021 V0B Secure Smart Card Controller, Version 1.4, 2 November 2007, NXP Semiconductors Germany GmbH (confidential document)
- [5] Configuration List, BSI-DSZ-CC-0404/0410/0411, Evaluation of the NXP P5Cx012/02x/040/073/080/144 family of Secure Smart Card Controllers, Version 1.6, NXP Semiconductors Germany GmbH, 09. July 2008 (confidential document)
- [6] Assurance Continuity Maintenance Report BSI-DSZ-CC-0404-2007-MA-01, 28 September 2007, NXP Secure Smart Card Controller P5CD012V0B with specific IC Dedicated Software, BSI
- [7] Assurance Continuity Maintenance Report BSI-DSZ-CC-0404-2007-MA-02, 17 December 2007, NXP Secure Smart Card Controller P5CD040V0B with specific IC Dedicated Software, BSI
- [8] Assurance Continuity Maintenance Report BSI-DSZ-CC-0404-2007-MA-03, 30 April 2008, NXP Secure Smart Card Controller P5CD040V0B, P5CC040V0B, P5CD020V0B, P5CC021V0B and P5CD012V0B with specific IC Dedicated Software, BSI
- [9] ETR for Composition, NXPP5CD040V0B Secure Smart Card Controller, Version 1.2, 29 April 2008 (confidential document)
- [10] Electrical Test Specification, ETS 2, P5CD144, P5CD080, P5CD040, Rev. 6.0, 2 July 2008, NXP Semiconductors Germany GmbH